IN THE UNITED STATES PATENT AND TRADEMARK OFFICE Filing Date July 3, 2003 Inventor Luan C. Tran Assignee Micron Technology. Inc. Examiner D. le Title: Methods of Forming Conductive Capacitor Plugs, Methods of Forming Capacitor Contact Openings, and Methods of Forming Memory Arrays

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether all the submitted references are prior art.

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Dated: 1227/04

Respectfully submitted.

James D. Shaurette Reg. No. 39,833

01/03/2005 HALI11 00000064 10612839

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